INFORMATION DISCLOSURE	ATTY. DOCKET NO.	SERIAL NO.	
CITATION	4105-1	n/a 10/568,943	
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	OLACC	CLUDOL ACC	FILING DATE
/PWH/	2003/0169672	09/2003	NAME Onoe et al.	CLASS		IF APPROPRIATE
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	2004/0047245	03/2004	Onoe et al.	0000000000000000	9999	
	2004/0246879	12/2004	Onoe et al.	100000000000000000000000000000000000000	3000000007777777999999X	
	5,864,445	01/1999	Bennin et al.	10000005555555555555		
W	6,418,091	07/2002	Hirokane et al.	99000005555999900	000000000000000000000000000000000000000	
/PWH/	7,020,064	03/2006	Kim et al.	000000000000000000000000000000000000000		
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						TRANSI	ATION
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
/PWH/	1 351 939	05/1974	GB	100000000000000000000000000000000000000	50000000000000000000000000000000000000		
	55 139643	10/1980	ЛР	200000000000000000000000000000000000000	000000000000000000000000000000000000000	ABSTRACT	
	59-22250	02/1984	JР	566660000000000	000000000000000000000000000000000000000	ABSTRACT	
	63-001175	01/1988	JP	000000000000000000000000000000000000000	000000000000000000000000000000000000000	ABSTRACT	
	06-267122	09/1994	JР	500000000000000000000000000000000000000	000000000000000000000000000000000000000	ABSTRACT	
8	08-212604	08/1996	JP	100000000000000	000000000000000000000000000000000000000		<del></del>
	09-097457	04/1997	JP	000000000000000000000000000000000000000	000000000000000000000000000000000000000	ABSTRACT	
	09-153235	06/1997	JР		000000000000000000000000000000000000000	ABSTRACT	
	09-222430	08/1997	JР	555555555000000	000000000000000000000000000000000000000	ABSTRACT	
0008	10-334525	12/1998	JР	000000000000000000000000000000000000000	***************************************	ABSTRACT	
	11-045467	02/1999	ЛР	200000000000000000000000000000000000000	000000000000000000000000000000000000000	ABSTRACT	
	11-176033	07/1999	ЛР	000000000000000000000000000000000000000	>0000000000000000000000000000000000000	ABSTRACT	
	1 333 436	08/2003	EP	200000000000000000000000000000000000000	***************************************		
	1 369 864	12/2003	EP	100000000000000000000000000000000000000			
\/	1 381 042	01/2004	EP	000000000000000000000000000000000000000	000000000000000000000000000000000000000		
V	1 398 779	03/2004	EP	200000000000000000000000000000000000000	000000000000000000000000000000000000000		
/PWH/	1 398 780	03/2004	EP	200000000000000000000000000000000000000	500000000000000000000000000000000000000		

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×	2004/0047245	03/2004	Onoe et al.	10000000000000000000000000000000000000
00000	2004/0246879	12/2004	Onoe et al.	60600000000000000000000000000000000000
	5,864,445	01/1999	Bennin et al.	000000000000000000000000000000000000000
V	6,418,091	07/2002 -	Hirokane et al.	222222202222222222222222222222222222222
/PWH/	7,020,064	03/2006	Kim et al.	30000000000000000000000000000000000000
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	DOCUMENT	DATE	COUNTRY	CLASS SUB	CLASS YES	NO
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0000	59-22250	02/1984	JP	300000000000000000000000000000000000000	ABSTRACT	
	63-001175	01/1988	JP	200000000000000000000000000000000000000	ABSTRACT	
	06-267122	09/1994	JP	<u> </u>	ABSTRACT	
	08-212604	08/1996	JP	100000000000000000000000000000000000000	200000000X	
	09-097457	04/1997	JР	000000000000000000000000000000000000000	ABSTRACT	
	09-153235	06/1997	JP	000000000000000000000000000000000000000	ABSTRACT	
	09-222430	08/1997	JР		ABSTRACT	
	10-334525	12/1998	JP	i0000000000000000000000000000000000000	ABSTRACT	
	11-045467	02/1999	JP	100000000000000000000000000000000000000	ABSTRACT	
8	11-176033	07/1999	JP	***************************************	- ABSTRACT	
	1 333 436	08/2003	EP	9753000000000000000000000000000000000000	BASSOC	
	1 369 864	12/2003	EP	00000000000000000000000000000000000000	900998	
	1 381 042	01/2004	EP	555555555555555555555555555555555555555	0688000	
V	1 398 779	03/2004	EP	X0000000000000000000000000000000000000	000000000	
/PWH/	1 398 780	03/2004	EP	100000000000000000000000000000000000000		

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